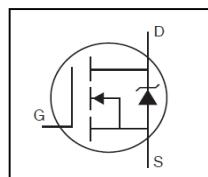


- Advanced Process Technology
- Ultra Low On-Resistance
- Isolated Package
- High Voltage Isolation = 2.5KVRMS ⑤
- Sink to Lead Creepage Dist. = 4.8mm
- Fully Avalanche Rated
- Lead-Free



HEXFET® Power MOSFET

V_{DSS}	55V
R_{DS(on)}	0.008Ω
I_D	64A



TO-220 Full-Pak

G	D	S
Gate	Drain	Source

Description

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The TO-220 Fullpak eliminates the need for additional insulating hardware in commercial-industrial applications. The moulding compound used provides a high isolation capability and a low thermal resistance between the tab and external heatsink. This isolation is equivalent to using a 100 micron mica barrier with standard TO-220 product. The Fullpak is mounted to a heatsink using a single clip or by a single screw fixing.

Base Part Number	Package Type	Standard Pack		Orderable Part Number
		Form	Quantity	
IRFI3205PbF	TO-220 Full-Pak	Tube	50	IRFI3205PbF

Absolute Maximum Ratings

Symbol	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V	64	A
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V	45	
I _{DM}	Pulsed Drain Current ①⑥	390	
P _D @ T _C = 25°C	Maximum Power Dissipation	63	W
	Linear Derating Factor	0.42	W/°C
V _{GS}	Gate-to-Source Voltage	± 20	V
E _{AS}	Single Pulse Avalanche Energy (Thermally Limited) ②⑥	480	mJ
I _{AR}	Avalanche Current ①⑥	59	A
E _{AR}	Repetitive Avalanche Energy ①	6.3	mJ
dv/dt	Peak Diode Recovery dv/dt③⑥	5.0	V/ns
T _J	Operating Junction and	-55 to + 175	°C
T _{STG}	Storage Temperature Range		
	Soldering Temperature, for 10 seconds (1.6mm from case)		
	Mounting torque, 6-32 or M3 screw	10 lbf•in (1.1N•m)	

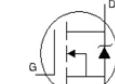
Thermal Resistance

Symbol	Parameter	Typ.	Max.	Units
R _{θJC}	Junction-to-Case	—	2.4	°C/W
R _{θJA}	Junction-to-Ambient	—	65	

Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	55	—	—	V	$V_{GS} = 0V, I_D = 250\mu\text{A}$
$\Delta V_{(\text{BR})\text{DSS}}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.057	—	V/ $^\circ\text{C}$	Reference to 25°C , $I_D = 1\text{mA}$ ⑥
$R_{\text{DS}(\text{on})}$	Static Drain-to-Source On-Resistance	—	—	0.008	Ω	$V_{GS} = 10V, I_D = 34\text{A}$
$V_{GS(\text{th})}$	Gate Threshold Voltage	2.0	—	4.0	V	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$
g_{fs}	Forward Trans conductance	42	—	—	S	$V_{DS} = 25V, I_D = 59\text{A}$ ⑥
I_{DSS}	Drain-to-Source Leakage Current	—	—	25	μA	$V_{DS} = 55V, V_{GS} = 0V$
		—	—	250		$V_{DS} = 44V, V_{GS} = 0V, T_J = 150^\circ\text{C}$
I_{GSS}	Gate-to-Source Forward Leakage	—	—	100	nA	$V_{GS} = 20V$
	Gate-to-Source Reverse Leakage	—	—	-100		$V_{GS} = -20V$
Q_g	Total Gate Charge	—	—	170	nC	$I_D = 59\text{A}$
Q_{gs}	Gate-to-Source Charge	—	—	32		$V_{DS} = 44V$
Q_{gd}	Gate-to-Drain Charge	—	—	74		$V_{GS} = 10V$, See Fig. 6 and 13 ④⑥
$t_{d(\text{on})}$	Turn-On Delay Time	—	14	—	ns	$V_{DD} = 28V$
t_r	Rise Time	—	100	—		$I_D = 59\text{A}$
$t_{d(\text{off})}$	Turn-Off Delay Time	—	43	—		$R_G = 2.5\Omega$
t_f	Fall Time	—	70	—		$R_D = 0.39\Omega$, See Fig. 10 ④⑥
L_D	Internal Drain Inductance	—	4.5	—	nH	Between lead, 6mm (0.25in.) from package and center of die contact :
L_S	Internal Source Inductance	—	7.5	—		
C_{iss}	Input Capacitance	—	4000	—	pF	$V_{GS} = 0V$
C_{oss}	Output Capacitance	—	1300	—		$V_{DS} = 25V$
C_{rss}	Reverse Transfer Capacitance	—	480	—		$f = 1.0\text{MHz}$, See Fig. 5 ⑥
C	Drain to Sink Capacitance	—	12	—		$f = 1.0\text{MHz}$

Source-Drain Ratings and Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)	—	—	64	A	MOSFET symbol showing the integral reverse p-n junction diode.
I_{SM}	Pulsed Source Current (Body Diode) ①⑥	—	—	390		
V_{SD}	Diode Forward Voltage	—	—	1.3	V	$T_J = 25^\circ\text{C}, I_S = 34\text{A}, V_{GS} = 0V$ ④
t_{rr}	Reverse Recovery Time	—	110	170	ns	$T_J = 25^\circ\text{C}, I_F = 59\text{A}$
Q_{rr}	Reverse Recovery Charge	—	450	680	nC	$di/dt = 100\text{A}/\mu\text{s}$ ④⑥
t_{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L_S+L_D)				

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- ② Starting $T_J = 25^\circ\text{C}$, $L = 190\mu\text{H}$, $R_G = 25\Omega$, $I_{AS} = 59\text{A}$ (See fig. 12)
- ③ $I_{SD} \leq 59\text{A}$, $di/dt \leq 290\text{A}/\mu\text{s}$, $V_{DD} \leq V_{(\text{BR})\text{DSS}}$, $T_J \leq 175^\circ\text{C}$.
- ④ Pulse width $\leq 300\mu\text{s}$; duty cycle $\leq 2\%$.
- ⑤ $t=60\text{s}$, $f=60\text{Hz}$
- ⑥ Uses IRF3205 data and test conditions.

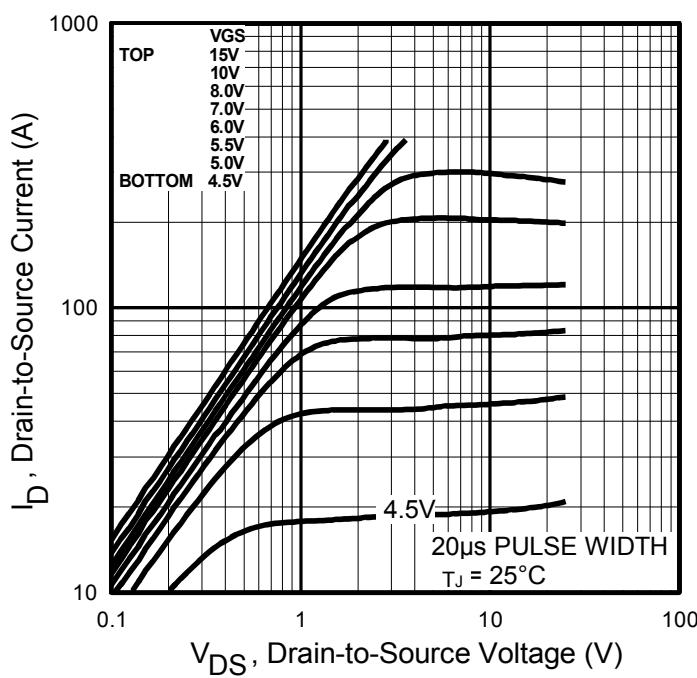


Fig. 1 Typical Output Characteristics

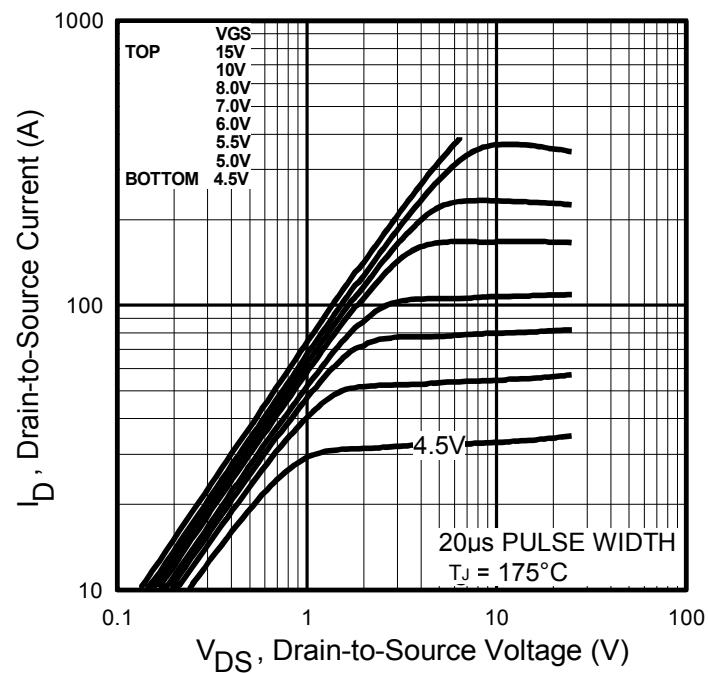


Fig. 2 Typical Output Characteristics

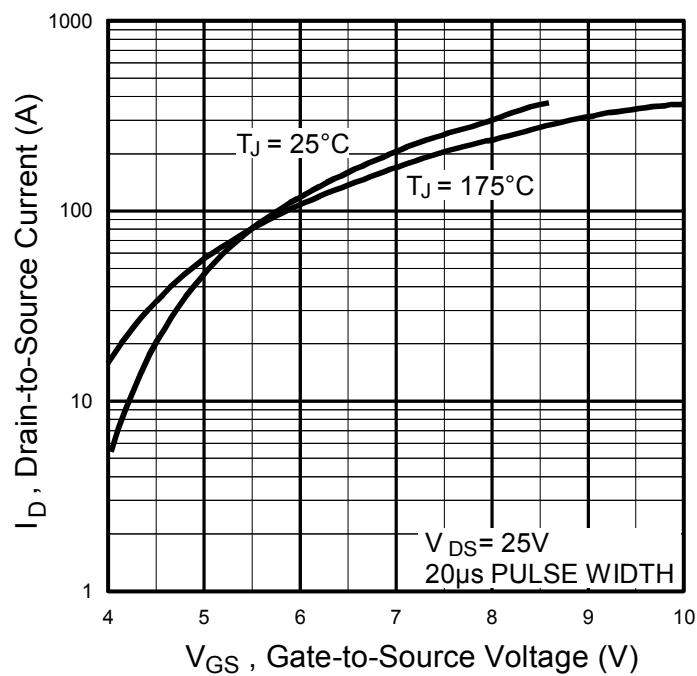


Fig. 3 Typical Transfer Characteristics

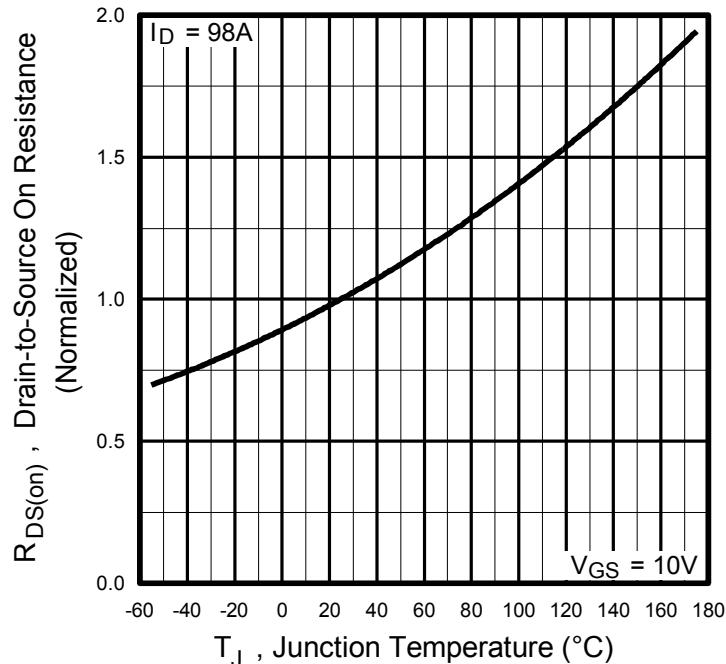


Fig. 4 Normalized On-Resistance vs. Temperature

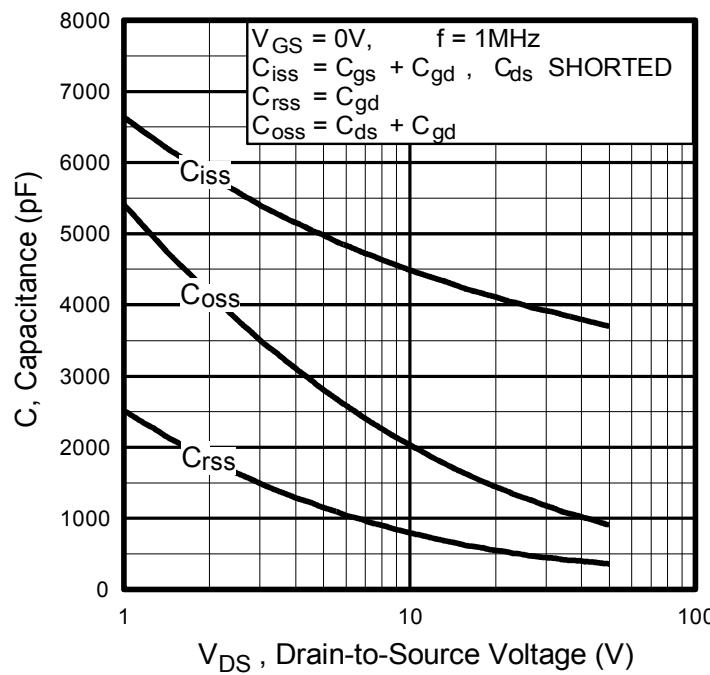


Fig 5. Typical Capacitance vs.
Drain-to-Source Voltage

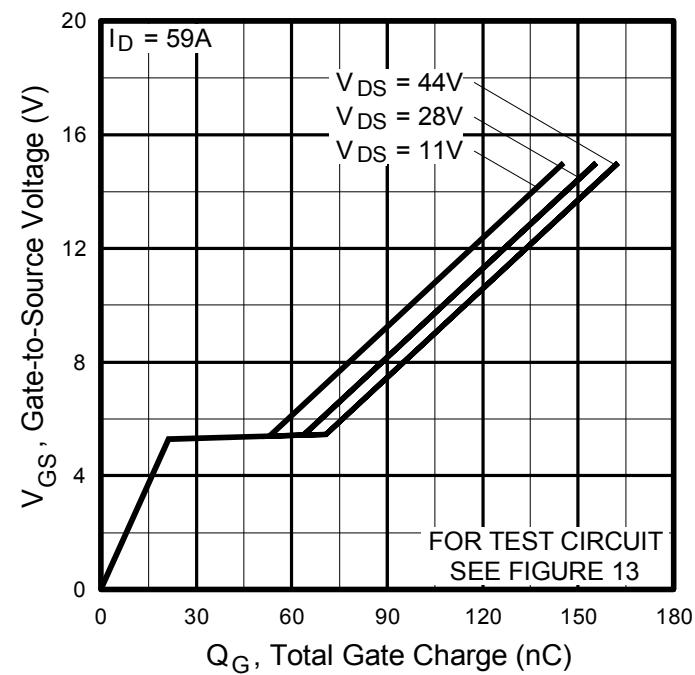


Fig 6. Typical Gate Charge vs.
Gate-to-Source Voltage

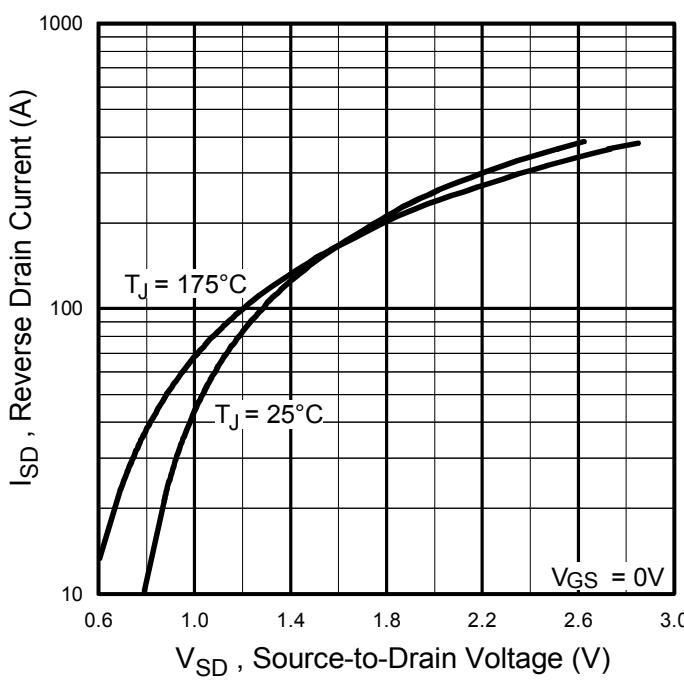


Fig. 7 Typical Source-to-Drain Diode
Forward Voltage

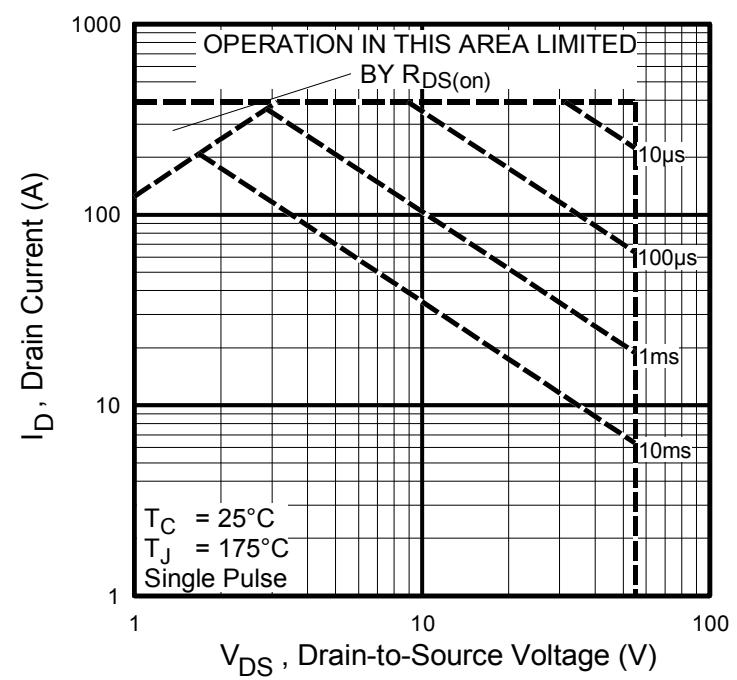


Fig 8. Maximum Safe Operating Area

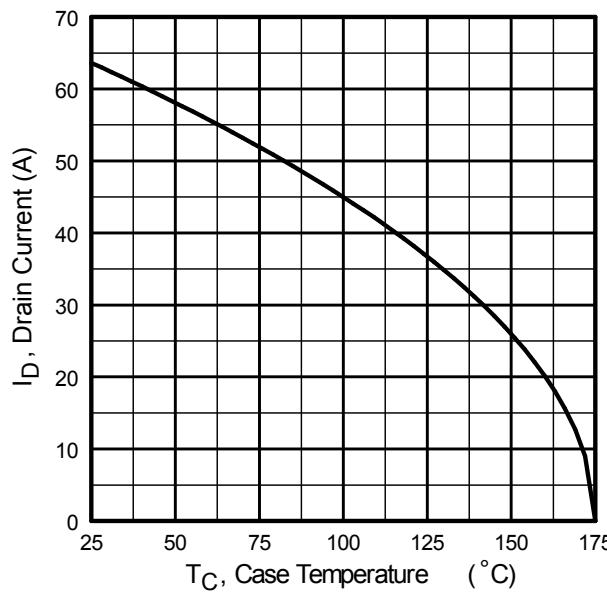


Fig 9. Maximum Drain Current vs. Case Temperature

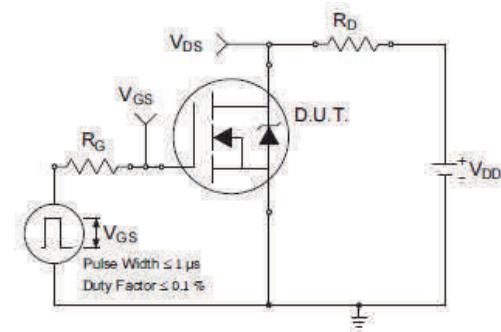


Fig 10a. Switching Time Test Circuit

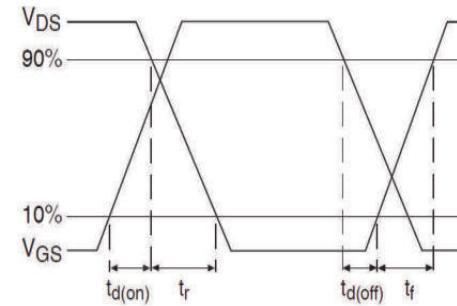


Fig 10b. Switching Time Waveforms

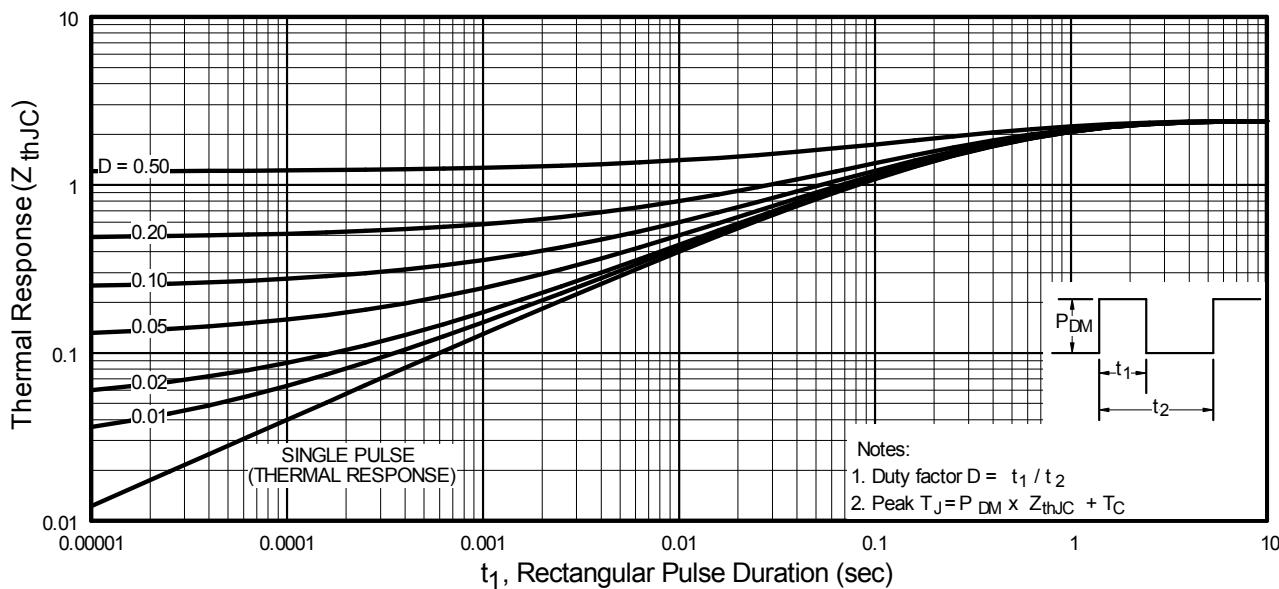


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

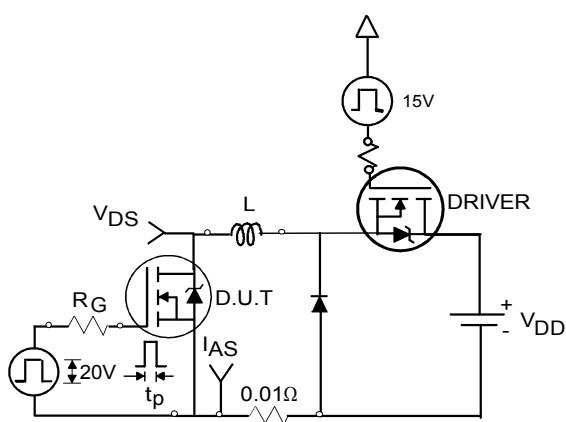


Fig 12a. Unclamped Inductive Test Circuit

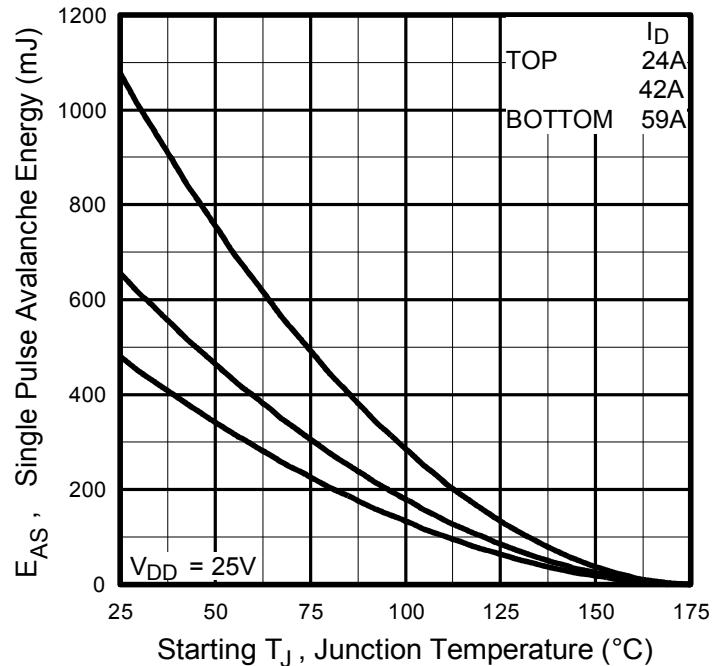


Fig 12c. Maximum Avalanche Energy vs. Drain Current

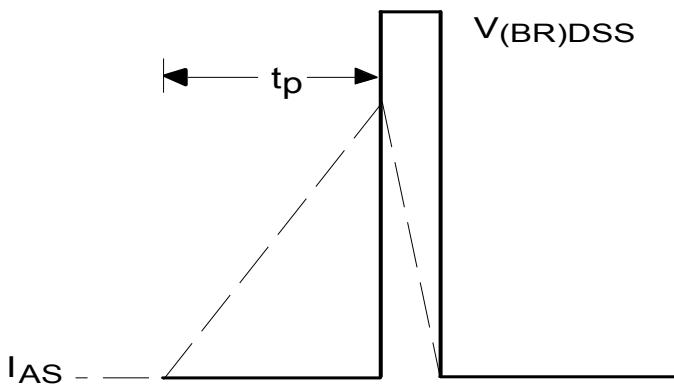


Fig 12b. Unclamped Inductive Waveforms

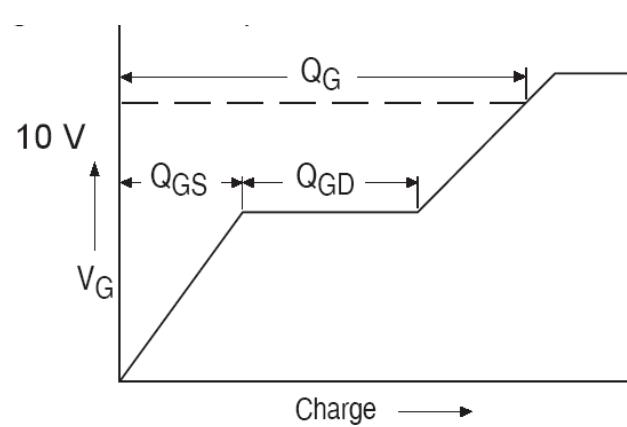


Fig 13a. Gate Charge Waveform

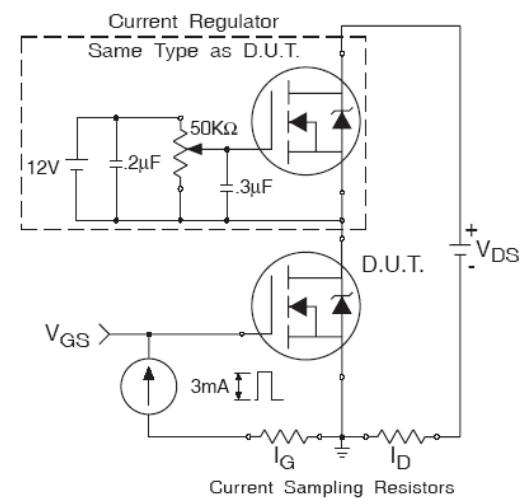
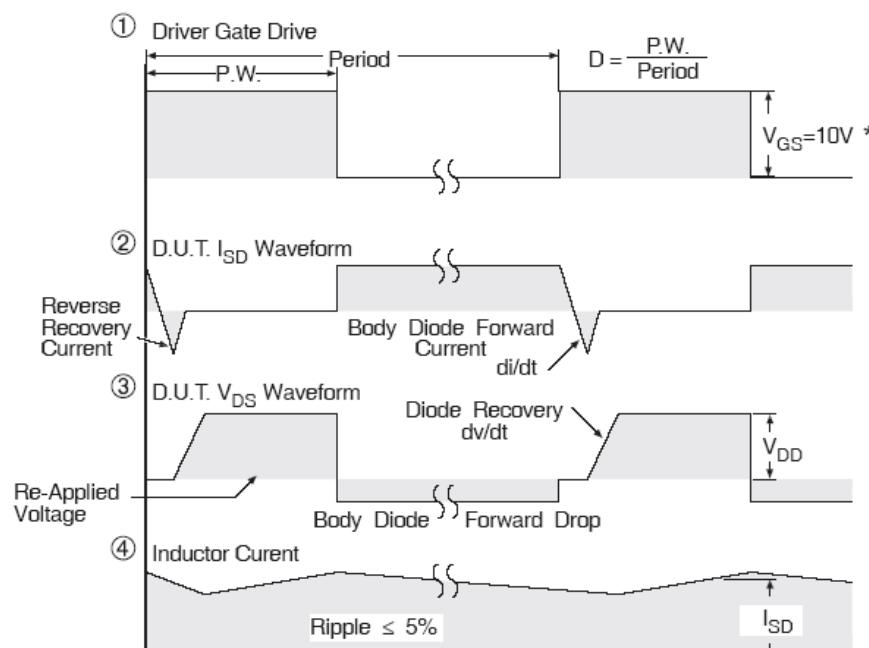
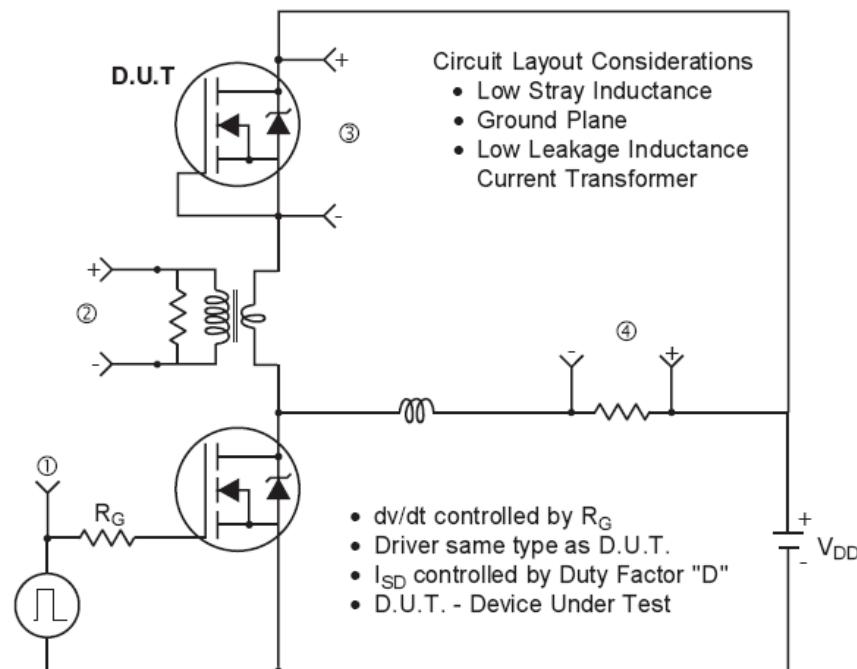


Fig 13b. Gate Charge Test Circuit

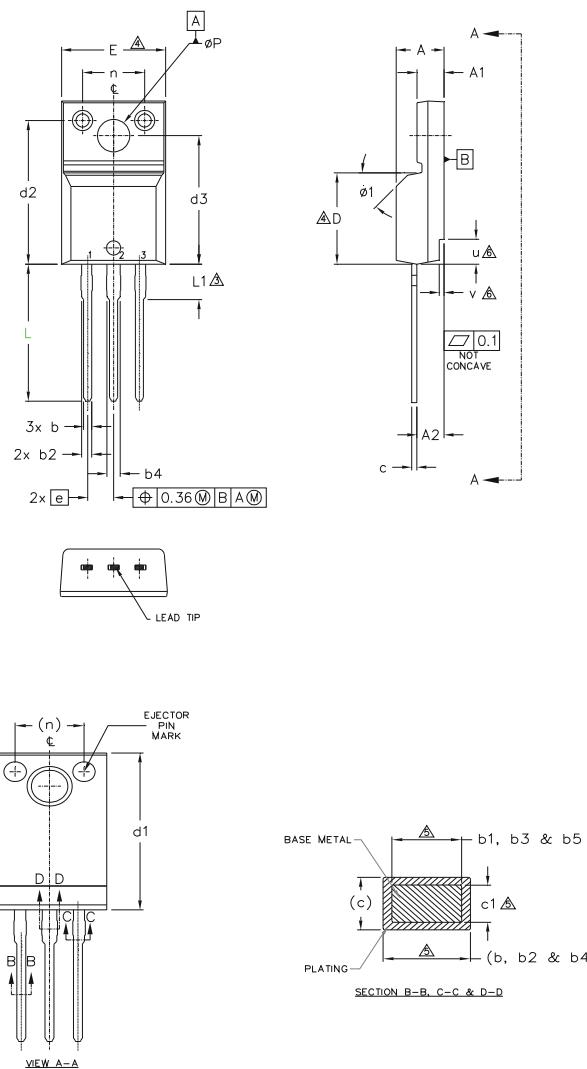
Peak Diode Recovery dv/dt Test Circuit



* $V_{GS} = 5V$ for Logic Level Devices

Fig 14. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

TO-220 Full-Pak Package Outline (Dimensions are shown in millimeters (inches))



NOTES

1.0 DIMENSIONING AND TOLERANCING AS PER ASME Y14.5 M- 1994.

2.0 DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

3.0 LEAD DIMENSION AND FINISH UNCONTROLLED IN L1.

4.0 DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTER MOST EXTREMES OF THE PLASTIC BODY.

5.0 DIMENSION b1, b3, b5 & c1 APPLY TO BASE METAL ONLY.

6.0 STEP OPTIONAL ON PLASTIC BODY DEFINED BY DIMENSIONS u & v.

7.0 CONTROLLING DIMENSION : INCHES.

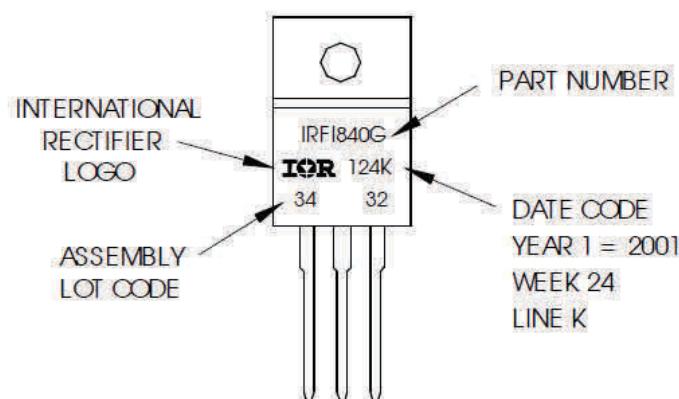
S Y M B O L	DIMENSIONS				N O T E S	
	MILLIMETERS		INCHES			
	MIN.	MAX.	MIN.	MAX.		
A	4.57	4.83	.180	.190		
A1	2.57	2.82	.101	.111		
A2	2.51	2.92	.099	.115		
b	0.61	0.94	.024	.037		
b1	0.61	0.89	.024	.035	5	
b2	0.76	1.27	.030	.050		
b3	0.76	1.22	.030	.048	5	
b4	1.02	1.52	.040	.060		
b5	1.02	1.47	.040	.058	5	
c	0.33	0.63	.013	.025		
c1	0.33	0.58	.013	.023	5	
D	8.66	9.80	.341	.386		
d1	15.80	16.13	.622	.635		
d2	13.97	14.22	.550	.560		
d3	12.29	12.93	.484	.509		
E	9.63	10.74	.379	.423	4	
e	2.54	BSC	.100	BSC		
L	13.21	13.72	.520	.540		
L1	3.10	3.68	.122	.145	3	
n	6.05	6.60	.238	.260		
øP	3.05	3.45	.120	.136		
u	2.39	2.49	.094	.098	6	
v	0.41	0.51	.016	.020	6	
ø1	—	45°	—	45°		

LEAD ASSIGNMENTS

HEXFET

IGBTs, CoPACK

1. – GATE
2. – COLLECTOR
3. – Emitter



TO-220AB Full-Pak packages are not recommended for Surface Mount Application.

Note: For the most current drawing please refer to website at <http://www.irf.com/package/>

Qualification Information

Qualification Level	Industrial (per JEDEC JESD47F) [†]	
Moisture Sensitivity Level	TO-220 Full-Pak	N/A
RoHS Compliant	Yes	

[†] Applicable version of JEDEC standard at the time of product release.

Revision History

Date	Comments
04/27/2017	<ul style="list-style-type: none"> Changed datasheet with Infineon logo - all pages. Corrected Package Outline on page 8. Added disclaimer on last page.

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